## Notice of References Cited

Application/Control No. 10/619,593	Applicant(s)/ Reexaminati LIN, HAI-CH	
Examiner	Art Unit	
Allen J. Flanigan	3753	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,072,787	12-1991	Nakamichi, Niro	165/80.3
	В	US-5,518,071 A	05-1996	Lee, Yong N.	165/185
	С	US-5,158,136 A	10-1992	Azar, Kaveh	165/185
	D	US-6,371,200 B1	04-2002	Eaton, Deran S.	165/80.3
	Ε	US-6,460,609 B1	10-2002	Cho et al.	165/80.3
	F	US-5,734,552	03-1998	Krein, Paul C.	361/695
	G	US-5,957,194 A	09-1999	Azar, Kaveh	165/80.3
	Н	US-6,637,502 B1	10-2003	North et al.	165/80.3
	ı	US-6,533,028 B2	03-2003	Sato, Kaoru	165/80.3
	J	US-5,694,295	12-1997	Mochizuki et al.	361/699
	K	US-2002/0109970 A1	08-2002	Yang et al.	361/695
	L	US-			
	М	US-	i		

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003243586 A	08-2003	Japan	IWATA, AKIRA	H01L 23/36
	0	JP 10012781 A	01-1998	Japan	HONMA et al.	H01L 23/467
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.